

Application/Control No.	Applicant(s)/Patent under Reexamination
09/682,755	TOYAMA ET AL.
Examiner	Art Unit
John M. Villagoo	2612

	SEAR	CHED	
Class	Subclass	Date	Examiner
. 348	207.1 211.3 231.2 231.3 231.6 552	7/6/2005	JV
707	3 6	7/6/2005	JV
709	212 213 216	7/6/2005	JV
709	217 219 231	7/6/2005	JV
709	238 239	7/6/2005	JV

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOT (INCLUDING SEARCH S	ES STRATEGY	')
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